

Fig.1 Wide scan spectrum of XPS measured from an RT deposited aluminum silicate on Si.

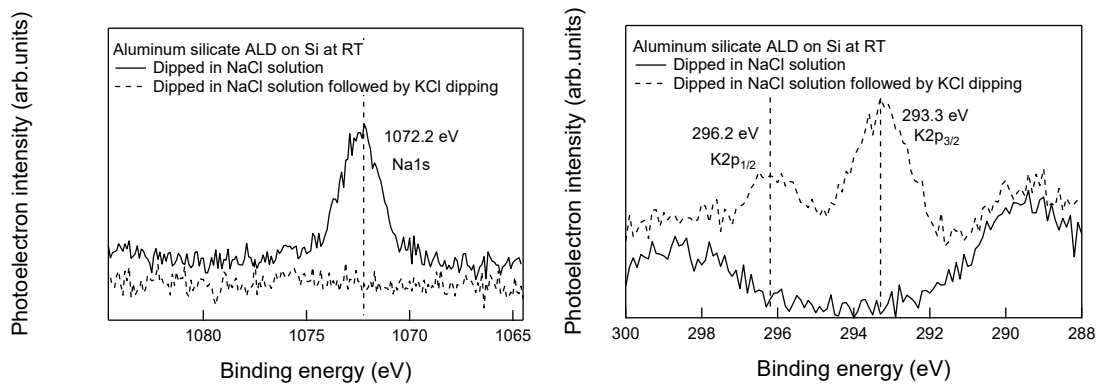


Fig. 2 XPS spectra of Na 1s and K 2p measured from the aluminum silicate film, treated by an NaCl solution, followed by the KCl solution treatment.